Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,628	BAQAI ET AL.
Examiner	Art Unit
Wenneng Chen	2624

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US-PUPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) - See search history printout.	6/13/08	Zui
	6/26/06	
GAST (updated)	4/29/57	m
EAST (updated)	6/14/27	un
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